

**Search Notes**

Application/Control No.

10/614,056

Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

ANDO, TAKESHI

Art Unit

2683

**SEARCHED**

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| 455   | 432.1    | 4/21 | CH.      |
| 379   | 130      | 4/19 | CH       |
| 455   | 417      | 4/19 | CH       |
| 455   | 432.2    | 4/20 | CH       |
| 704   | 257      | 4/20 | CH       |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|                | DATE    | EXMR |
|----------------|---------|------|
| Class/Subclass | 4/21/05 | CH.  |
| Citations/IDS  | 4/19    | CH.  |
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